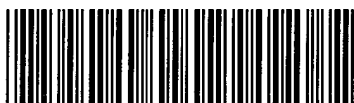


Search Notes

Application/Control No.

10/644,893

Examiner

Brian Young

Applicant(s)/Patent under
Reexamination

YUN ET AL.

Art Unit

2819

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 341 | 155 | 1/31/2005 | BY |
| // | 137 | | BY |
| 348 | 294 | | BY |
| | 295 | | BY |
| | 300 | | BY |
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| | 302 | | BY |
| | 303 | | BY |
| | 308 | | BY |
| 257 | 222 | | BY |
| 250 | 208.1 | | BY |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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